	Application No.	Applicant(s)
Notice of Allowability	09/901,438	HASEGAWA ET AL.
	Examiner	Art Unit
	Christopher R. Magee	2653
The MAILING DATE of this communication app All claims being allowable, PROSECUTION ON THE MERITS IS herewith (or previously mailed), a Notice of Allowance (PTOL-85 NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT I of the Office or upon petition by the applicant. See 37 CFR 1.31	S (OR REMAINS) CLOSED in this a b) or other appropriate communication. RIGHTS. This application is subject	pplication. If not included on will be mailed in due course. THIS
1. This communication is responsive to the IDS filed 06/07/2	<u>2005</u> .	
2. The allowed claim(s) is/are 17-46.		
 3. Acknowledgment is made of a claim for foreign priority to a) All b) Some* c) None of the: 1. Certified copies of the priority documents have 2. Certified copies of the priority documents have 	ve been received.	
Copies of the certified copies of the priority deciments have Copies of the certified copies of the priority deciments have		
International Bureau (PCT Rule 17.2(a)).	ocuments have been received in this	s national stage application from the
* Certified copies not received:		
Applicant has THREE MONTHS FROM THE "MAILING DATE noted below. Failure to timely comply will result in ABANDON THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.		y complying with the requirements
 A SUBSTITUTE OATH OR DECLARATION must be subr INFORMAL PATENT APPLICATION (PTO-152) which given 	mitted. Note the attached EXAMINE ves reason(s) why the oath or declar	R'S AMENDMENT or NOTICE OF ration is deficient.
5. CORRECTED DRAWINGS (as "replacement sheets") mu	ust be submitted.	
(a) 🔲 including changes required by the Notice of Draftsper	rson's Patent Drawing Review (PTC	0-948) attached
1) 🗌 hereto or 2) 🔲 to Paper No./Mail Date	_	
(b) including changes required by the attached Examiner Paper No./Mail Date	r's Amendment / Comment or in the	Office action of
Identifying indicia such as the application number (see 37 CFR each sheet. Replacement sheet(s) should be labeled as such in	1.84(c)) should be written on the draw the header according to 37 CFR 1.121	rings in the front (not the back) of I(d).
 DEPOSIT OF and/or INFORMATION about the deposit attached Examiner's comment regarding REQUIREMENT 	osit of BIOLOGICAL MATERIAL FOR THE DEPOSIT OF BIOLOGIC	must be submitted. Note the CAL MATERIAL.
Attachment(s) 1. ☐ Notice of References Cited (PTO-892)	5. Notice of Informal	Patent Application (PTO-152)
 Notice of Neiterences Gled (F10-032) District Notice of Draftperson's Patent Drawing Review (PTO-948) 		•
	Paper No./Mail Da	ate
 Information Disclosure Statements (PTO-1449 or PTO/SB/ Paper No./Mail Date 06/07/2005 	(08), 7. ☐ Examiner's Amend	ament/Comment
4. Examiner's Comment Regarding Requirement for Deposit	8. X Examiner's Statem	nent of Reasons for Allowance
of Biological Material	9.	, .
12/20/2005		ANGEL CASTRO
12/20/2005 MAMAR —		ÁNGEL CASTRO PRIMARY EXAMINER

O.S. Patent and Trademark Office PTOL-37 (Rev. 7-05)

DETAILED ACTION

Election/Restrictions

1. Claims 1-16 and 47-78 are withdrawn from further consideration pursuant to 37 CFR 1.142(b), as being drawn to a nonelected species, there being no allowable generic or linking

claim. Applicant timely traversed the restriction (election) requirement in the reply filed on

12/27/2004.

2. Applicant's election of Species B (claims 17-46) in the reply filed on 12/27/2004 is

acknowledged. Because applicant did not distinctly and specifically point out the supposed

errors in the restriction requirement, the election has been treated as an election without traverse

(MPEP § 818.03(a)).

Priority

3. Receipt is acknowledged of papers submitted under 35 U.S.C. 119(a)-(d), which papers have been placed of record in the file.

Information Disclosure Statement

4. The information disclosure statement (IDS) submitted on 06/07/2005 was filed after the mailing date of the Notice of Allowance on 3/23/2005. The submission is in compliance with the provisions of 37 CFR 1.97. Accordingly, the examiner has considered the information disclosure statement.

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Reasons for Allowance

5. Claims 17-46 are allowed (renumbered as 1-30, respectively).

6. The following is an examiner's statement of reasons for allowance:

This application is for an EXCHANGE COUPLING FILM AND MAGNETORESISTIVE ELEMENT USING THE SAME.

• Claim 17 specifies an exchange coupling film, which requires:

"wherein second imaginary line in the diffraction diagrams of the antiferromagnetic layer and the ferromagnetic layer, the secondary imaginary lines each connecting the beam origin and a particular one of the diffraction spots which is given the same label in both the diffraction diagrams of the antiferromagnetic layer and the ferromagnetic layer and which is located in a direction other than the layer thickness direction when viewed from the beam origin, are not coincident with each other."

Fukuzawa et al. (US 6,338,899 B1) show a diffraction diagram of the antiferromagnetic layer with a dispersion angle of half value width in the <111> direction [Fig. 20; col. 50, lines 58]. Fukuzawa et al. do not teach and/or suggest a second imaginary line in the diffraction diagrams of the antiferromagnetic layer and the ferromagnetic layer, the secondary imaginary lines each connecting the beam origin and a particular one of the diffraction spots which is given the same label in both the diffraction diagrams of the antiferromagnetic layer and the ferromagnetic layer and which is located in a direction other than the layer thickness direction when viewed from the beam origin, are not coincident with each other as claimed in the present invention.

Fuke et al. (US 5,976,713) show an electron beam diffraction pattern of the antiferromagnetic layer oriented in one plane [Figs. 8 and 9; col. 8, lines 46-50]. Fuke et al. do

not teach and/or suggest a second imaginary line in the diffraction diagrams of the antiferromagnetic layer and the ferromagnetic layer, the secondary imaginary lines each connecting the beam origin and a particular one of the diffraction spots which is given the same label in both the diffraction diagrams of the antiferromagnetic layer and the ferromagnetic layer and which is located in a direction other than the layer thickness direction when viewed from the beam origin, are not coincident with each other as claimed in the present invention

Therefore, these features, in combination with other features of claim 17 are not anticipated by, nor made obvious over, the closest prior art of record Fukuzawa et al. (US 6,338,899 B1) and/or Fuke et al. (US 5,976,713).

• Claim 32 specifies an exchange coupling film, which requires:

"wherein a particular diffraction spot indicative of a particular crystal plane, located in a direction other than the layer thickness direction, appears only in one of the diffraction diagrams of the antiferromagnetic layer and the ferromagnetic layer."

Fukuzawa et al. (US 6,338,899 B1) show a diffraction diagram of the antiferromagnetic layer with a dispersion angle of half value width in the <111> direction (Fig. 20; col. 50, lines 58). Fukuzawa et al. do not teach and/or suggest a particular diffraction spot indicative of a particular crystal plane, located in a direction other than the layer thickness direction, appears only in one of the diffraction diagrams of the antiferromagnetic layer and the ferromagnetic layer as claimed in the present invention.

Fuke et al. (US 5,976,713) show an electron beam diffraction pattern of the antiferromagnetic layer oriented in one plane [Figs. 8 and 9; col. 8, lines 46-50]. Fuke et al. do not teach and/or suggest a particular diffraction spot indicative of a particular crystal plane, located in a direction other than the layer thickness direction, appears only in one of the

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diffraction diagrams of the antiferromagnetic layer and the ferromagnetic layer as claimed in the

present invention.

Therefore, these features, in combination with other features of claim 32 are not

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anticipated by, nor made obvious over, the closest prior art of record Fukuzawa et al. (US

6,338,899 B1) and/or Fuke et al. (US 5,976,713).

7. Any comments considered necessary by applicant must be submitted no later than the

payment of the issue fee and, to avoid processing delays, should preferably accompany the issue

fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for

Allowance."

Conclusion

8. Any inquiry concerning this communication or earlier communications from the

examiner should be directed to Christopher R. Magee whose telephone number is (571) 272-

7592. The examiner can normally be reached on M-F, 8: 00 am-5: 30 pm.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's

supervisor, William Korzuch can be reached on (571) 272-7589. The fax phone number for the

organization where this application or proceeding is assigned is 703-872-9306.

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Information regarding the status of an application may be obtained from the Patent

Application Information Retrieval (PAIR) system. Status information for published applications

may be obtained from either Private PAIR or Public PAIR. Status information for unpublished

applications is available through Private PAIR only. For more information about the PAIR

system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR

system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

December 20, 2005

Christopher R. Magee

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